



| | |
|---|--|
| Title of Change: | Wafer Fab Transfer for Trench 6 MOSFET Technology to Global Foundries in New York, US. |
| Proposed Changed Material First Ship Date: | 08 Jan 2022 or earlier if approved by customer |
| Current Material Last Order Date: | 26 Nov 2021 <i>Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.</i> |
| Current Material Last Delivery Date: | 07 Jan 2022 <i>The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory</i> |
| Product Category: | Active components – Discrete components |
| Contact information: | Contact your local ON Semiconductor Sales Office or Ammar.Anuar@onsemi.com |
| PCN Samples Contact: | Contact your local ON Semiconductor Sales Office to place sample order or <PCN.samples@onsemi.com> . Sample requests are to be submitted no later than 45 days after publication of this change notification. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements. |
| Sample Availability Date: | 01 Jan 2021 |
| PPAP Availability Date: | 01 Jan 2021 |
| Additional Reliability Data: | Contact your local ON Semiconductor Sales Office or Robert.Baran@onsemi.com |
| Type of Notification: | This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 months prior to implementation of the change or earlier upon customer approval. ON Semiconductor will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 45 days of delivery of this notice. To do so, contact PCN.Support@onsemi.com . |
| Change Category | |
| Category | Type of Change |
| Process - Wafer Production | Move of all or part of wafer fab to a different location/site/subcontractor, New wafer diameter |
| Test Flow | Move of all or part of electrical wafer test and/or final test to a different location/site/subcontractor |
| Description and Purpose: | |
| <p>This Product Change Notification, is the continuation from IPCN22966ZC, which is intended to increase capacity for ON's automotive 30V and 40V Trench 6 MOSFET technology products by transferring wafer fabrication for these products to the Global Foundries Fab located in New York, US.</p> <p>The changes include transferring wafer fabrication, back grind and back metal, to Global Foundries, and utilizing 300mm instead of 200mm diameter wafers. And while the assembly location remains unchanged (at ON Semiconductor, Seremban, Malaysia), wafer saw and die attach tooling are being updated to accommodate 300mm wafers.</p> <p>There is no change to the orderable part number.</p> <p>There is no product marking change as a result of this change.</p> | |



| | Before Change | After Change | | |
|---|---|---|-----------|---------|
| Wafer Fabrication Site | ON Aizu, Japan ON Gresham, US | <u>Global Foundries, US</u> | | |
| Wafer Diameter | 200mm (existing sites) | 300mm (Global Foundries) | | |
| Wafer Probe Site | ON Seremban, Malaysia | <u>Global Foundries, US</u> | | |
| Back Grind, Back Metal Site | ON ISMF, Malaysia | <u>Global Foundries, US</u> | | |
| Reason / Motivation for Change: | Source/Supply/Capacity Changes Process/Materials Change | | | |
| Anticipated impact on fit, form, function, reliability, product safety or manufacturability: | The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded. No anticipated impacts. | | | |
| Sites Affected: | | | | |
| ON Semiconductor Sites | External Foundry/Subcon Sites | | | |
| On Semiconductor Gresham, United States | GlobalFoundries, Fab 10, New York, US | | | |
| ON Semiconductor Aizu, Japan | | | | |
| ON Semiconductor Seremban, Malaysia | | | | |
| Marking of Parts/ Traceability of Change: | Material will be traceable with ONs lot trace code & tracking | | | |
| Reliability Data Summary: | | | | |
| QV DEVICE NAME (DIE QUAL): NVMF55C404NL | | | | |
| RMS: 66099, 67744, 67566, 67567 | | | | |
| PACKAGE: SO8FL-HE | | | | |
| Test | Specification | Condition | Interval | Results |
| HTRB | JESD22-A108 | Ta=175°C, 100% max rated Vds | 2016 hrs | 0/231 |
| HTGB | JESD22-A108 | Ta=175°C, 100% max rated Vgss | 2016 hrs | 0/231 |
| HTSL | JESD22-A103 | Ta= 175°C | 2016 hrs | 0/231 |
| IOL | MIL-STD-750 (M1037) AEC-Q101 | Ta=+25°C, delta Tj=100°C On/off =2 min | 30000 cyc | 0/231 |
| TC | JESD22-A104 | Ta= -55°C to +150°C | 1000 cyc | 0/231 |
| HAST | JESD22-A110 | 130°C, 85% RH, 18.8psig, bias | 192 hrs | 0/231 |
| uHAST | JESD22-A118 | 130°C, 85% RH, 18.8psig, unbiased | 96 hrs | 0/231 |
| PC | J-STD-020 JESD-A113 | MSL1 @ 260°C | | |
| RSH | JESD22- B106 | Ta = 265C, 10 sec | | 0/30 |
| QV DEVICE NAME (DIE QUAL): NVMF55C404N | | | | |
| RMS: 66100 | | | | |
| PACKAGE: SO8FL-HE | | | | |
| Test | Specification | Condition | Interval | Results |
| HTGB | JESD22-A108 | Ta=175°C, 100% max rated Vgss | 2016 hrs | 0/231 |



Note: AEC-1 pager is attached.

To view attachments:

1. Download pdf copy of the PCN to your computer

2. Open the downloaded pdf copy of the PCN

3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field

4. Then click on the attached file/s

Electrical Characteristics Summary:

Electrical characteristics are not impacted.

List of Affected Parts:

Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the [PCN Customized Portal](#).

| Current Part Number | New Part Number | Qualification Vehicle |
|---------------------|-----------------|-------------------------------------|
| NVMF55C404NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C404NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C410NAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C410NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C410NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C423NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C423NLT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C426NAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C430NAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C430NLT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C430NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C442NAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C442NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NLT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C456NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF54C01NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF54C01NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF54C03NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |



| | | |
|-------------------|----|-------------------------------------|
| NVMFS4C03NT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS4C05NT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS4C05NT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS4C302NT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C404NAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C404NAFT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C404NLAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C404NLT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C404NLT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C404NT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C410NAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C410NLAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C410NLT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C410NLT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C410NT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C423NLAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C423NLT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C426NAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C426NT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C426NT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C430NAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C430NLAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C430NLAFT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C430NLT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C430NT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C442NAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C442NLAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C442NLAFT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C442NLT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C442NLT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C442NT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C450NAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C450NLAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C450NLT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C450NT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |



| | | |
|-------------------|----|-------------------------------------|
| NVMFS5C456NLAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C456NLT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C456NLT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C456NT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C460NLAFT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C460NLAFT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C460NLT1G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVMFS5C460NLT3G | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVTF5C405NTAG | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVTF5C413NTAG | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVTF5C413NTWG | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVTF5C453NLTAG | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |
| NVTF5C466NLTAG | NA | NVMFS5C404NLT1G, NVMFS5C404NWFT3G-K |

Japanese translation of the notification starts here.
通知の日本語訳はここから始まります。

Note: The Japanese version is for reference only. In case of any differences between the English and Japanese version, the English version shall control.

注：日本語版は参照用です。英語版と日本語版の違いがある場合は、英語版が優先されます。



| | | |
|-------------------|---|-----------------------------|
| 変更件名: | グローバルファウンドリー(ニューヨーク、米国)にて Trench 6 MOSFET テクノロジー製品のウェハー工場生産能力拡大 | |
| 初回出荷予定日: | 08 Jan 2022 またはお客様からの承認が得られた場合はそれ以前。 | |
| 現在の材料の最終注文日: | 26 Nov 2021 既存品の最終注文日以降の注文は、この PCN に記載されている変更後品の注文とみなされます。この日付より後の既存品(変更前品)の注文は、相互契約により変更前品の在庫状況に応じて履行されます。 | |
| 現在の材料の最終出荷日: | 07 Jan 2022 既存品(変更前品)の最終出荷日は、変更前品の製造および在庫の状況によって変更されることがあります。 | |
| 製品カテゴリ: | アクティブなコンポーネント - 個別コンポーネント | |
| 連絡先情報: | 現地のオン・セミコンダクター営業所または Ammar.Anuar@onsemi.com にお問い合わせください。 | |
| サンプル: | 現地のオン・セミコンダクター営業所に注文するか、また PCN.samples@onsemi.com にお問い合わせください。 サンプルは、この変更通知の発行から 45 日以内に要求してください。 サンプル納入時は、依頼日、数量、特別梱包材/ラベル条件によって異なります。 | |
| 追加の信頼性データ: | お客さまの地域のオン・セミコンダクター営業所または Robert.Baran@onsemi.com にお問い合わせください。 | |
| サンプル提供開始可能日: | 01 Jan 2021 | |
| PPAP 提供開始日: | 01 Jan 2021 | |
| 追加の信頼性データ: | お客さまの地域のオン・セミコンダクター営業所または Robert.Baran@onsemi.com にお問い合わせください。 | |
| 通知種別: | これは、お客様宛の最終製品 / プロセス変更通知 (FPCN) です。 FPCN は、変更実施の 12 か月前、またはお客様からの承認が得られた場合はそれ以前に発行されることがあります。 オン・セミコンダクターは、この通知の送付から 45 日以内に書面による問い合わせが行われたい限り、この変更希望およびその条件が受諾されたものとみなします。お問い合わせは、 PCN.Support@onsemi.com をお願いします。 | |
| 変更カテゴリ: | 変更種別 | |
| プロセス-ウェハー製造 | ウェハー工場の全て / 一部の異なる場所/拠点/外注への移管 新規ウェハー径 | |
| テストフロー | 電氣的ウェハー検査の全て / 一部または最終検査(あるいはその両方)を異なる場所 / 拠点 / 外注へ移管 | |
| 説明および目的: | <p>本製品変更通知は、IPC22966ZC からの続きであり、オンの車載用 30V および 40V Trench 6 MOSFET テクノロジー製品のウェハー製造を、米国ニューヨーク州にあるグローバルファウンドリー工場に移管することにより、生産能力の拡大を図ることを目的としています。</p> <p>変更は、ウェハー製造、バックグラインドおよびバックメタルのグローバルファウンドリーへの移管、そして 200mm ではなく 300mm 径のウェハーの使用が含まれます。</p> <p>また、組立拠点は変更されませんが(オンセミコンダクター、マレーシアのセレンバン)、300mm 径ウェハーに対応するようにウェハーソーとダイアタッチ設備が更新されています。</p> <p>オーダー可能な製品番号に変更はありません。</p> <p>本変更の結果として、製品マーキングに変更はありません。</p> | |
| | 変更前の表記 | 変更後の表記 |
| ウェハー製造拠点 | ON Aizu, Japan ON Gresham, US | <u>Global Foundries, US</u> |
| ウェハー径 | 200mm (existing sites) | 300mm (Global Foundries) |
| ウェハーブロープ拠点 | ON Seremban, Malaysia | <u>Global Foundries, US</u> |
| バックグラインド、バックメタル拠点 | ON ISMF, Malaysia | <u>Global Foundries, US</u> |



| 変更の理由 / 動機: | ソース/供給/能力変更プロセス/材料変更 | | | |
|---|---|---|-----------|-------|
| 適合性、形状、機能、信頼性、製品安全性、または製造可能性に関して見込まれる影響 | 製品は同じ製品仕様に基づいて認定および検証されています。製品は認定試験に正常に合格しています。潜在的な影響が確認される可能性があります。オン・セミコンダクターが PCN に関して実施する検査により、関連するリスクは検証および排除されます。 予想される影響はありません。 | | | |
| 影響を受ける拠点: | | | | |
| オン・セミコンダクター拠点: | | 外部製造工場 / 下請業者拠点: | | |
| On Semiconductor Gresham, United States | | GlobalFoundries, Fab 10, New York, US | | |
| ON Semiconductor Aizu, Japan | | | | |
| ON Semiconductor Seremban, Malaysia | | | | |
| 部品の表示 / 変更の追跡可能性: | 材料はオンのトレースコードとトラッキングにてトレースできます。 | | | |
| 信頼性データの要約: | | | | |
| デバイス名: (DIE QUAL): NVMF55C404NL | | | | |
| RMS: 66099,67744, 67566, 67567 | | | | |
| パッケージ: SO8FL-HE | | | | |
| テスト | 仕様 | 条件 | 間隔 | 結果 |
| HTRB | JESD22-A108 | Ta=175°C, 100% max rated Vds | 2016 hrs | 0/231 |
| HTGB | JESD22-A108 | Ta=175°C, 100% max rated Vgss | 2016 hrs | 0/231 |
| HTSL | JESD22-A103 | Ta= 175°C | 2016 hrs | 0/231 |
| IOL | MIL-STD-750 (M1037) AEC-Q101 | Ta=+25°C, delta Tj=100°C On/off =2 min | 30000 cyc | 0/231 |
| TC | JESD22-A104 | Ta= -55°C to +150°C | 1000 cyc | 0/231 |
| HAST | JESD22-A110 | 130°C, 85% RH, 18.8psig, bias | 192 hrs | 0/231 |
| uHAST | JESD22-A118 | 130°C, 85% RH, 18.8psig, unbiased | 96 hrs | 0/231 |
| PC | J-STD-020 JESD-A113 | MSL1 @ 260°C | | |
| RSH | JESD22- B106 | Ta = 265C, 10 sec | | 0/30 |
| デバイス名: (DIE QUAL) : NVMF55C404N | | | | |
| RMS : 66100 | | | | |
| パッケージ: SO8FL-HE | | | | |
| テスト | 仕様 | 条件 | 間隔 | 結果 |
| HTGB | JESD22-A108 | Ta=175°C, 100% max rated Vgss | 2016 hrs | 0/231 |
| 注 : AEC 1 ページャーを添付しています。 | | | | |
| 添付文書を見るには: | | | | |
| 1. ご使用のコンピューターに PDF 版の PCN をダウンロードします。 | | | | |
| 2. ダウンロードした PDF 版の PCN を開きます。 | | | | |
| 3. 添付欄を見るには、画面左 / 下部分のメニュー上にあるクリップ アイコンをクリックしてください。 | | | | |
| 4. 添付ファイルをクリックします | | | | |



電气的特性の要約:

電气的特性への影響はありません。

影響を受ける部品の一覧:

注: 標準の部品番号(既製品)のみが部品一覧に記載されます。本 PCN に影響を受けるカスタム 部品は、PCN メールのお客様の特定の PCN の付属文書、または PCN カスタマイズポータルに記載されています。

| 現在の部品番号 | 新部品番号 | 認定試験用ピークル |
|-------------------|-------|--|
| NVMF55C404NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C404NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C410NAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C410NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C410NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C423NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C423NLT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C426NAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C430NAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C430NLT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C430NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C442NAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C442NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NLT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |



| | | |
|-------------------|----|--|
| NVMF55C456NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF54C01NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF54C01NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF54C03NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF54C03NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF54C05NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF54C05NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF54C302NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C404NAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C404NAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C404NLAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C404NLT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C404NLT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C404NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C410NAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C410NLAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C410NLT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C410NLT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C410NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C423NLAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C423NLT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C426NAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |



| | | |
|-------------------|----|--|
| NVMF55C426NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C426NT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C430NAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C430NLAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C430NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C430NLT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C430NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C442NAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C442NLAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C442NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C442NLT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C442NLT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C442NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NLAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NLT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C450NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C456NLAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C456NLT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C456NLT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C456NT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C460NLAFT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |



| | | |
|-------------------|----|--|
| NVMF55C460NLAFT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C460NLT1G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVMF55C460NLT3G | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVTFS4C05NTAG | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVTFS4C13NTAG | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVTFS4C13NTWG | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVTFS5C453NLTAG | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |
| NVTFS5C466NLTAG | NA | NVMF55C404NLT1G, NVMF55C404NWFT3G-K |